Notice of References Cited Application/Control No. 10/534,536 Examiner HENOK G. HEYI Applicant(s)/Patent Under Reexamination FUKUSHIMA ET AL. Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-5,905,705 A	05-1999	Takeda et al.	360/51
*	В	US-2003/0161255 A1	08-2003	Kikuchi et al.	369/280
*	С	US-6,628,576 B1	09-2003	Watanabe et al.	369/30.17
*	D	US-2004/0145086 A1	07-2004	Yusa, Atsushi	264/328.11
*	Е	US-2004/0257970 A1	12-2004	Yamaga et al.	369/275.4
*	F	US-2005/0199778 A1	09-2005	Kadowaki et al.	250/201.5
*	G	US-2005/0254795 A1	11-2005	Muramatsu et al.	386/125
*	Н	US-2006/0098559 A1	05-2006	Hino et al.	369/275.1
*	I	US-7,050,386 B2	05-2006	Ueda, Eiji	369/275.4
*	J	US-7,420,889 B2	09-2008	Ishibashi et al.	369/44.13
	К	US-			
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 08-185632	07-1996	Japan	Matsuo Norimasa	G11B 7/007
	0					
	Р					
	Ø					
	R					
	S					
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	W	
	×	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.